

Notice of References Cited	Application/Control No. 10/730,898		Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0113871	06-2004	Kashio et al.	345/063
*	B	US-2003/0234753	12-2003	Tanaka, Yoshito	345/67
*	C	US-2003/0184502	10-2003	Makino, Mitsuyoshi	345/60
*	D	US-2003/0034937	02-2003	Kim, Jung Hun	345/63
*	E	US-2004/0164930	08-2004	Hashimoto et al.	345/060
*	F	US-2004/0095294	05-2004	Yamada, Kazuhiro	345/060
*	G	US-2002/0171609	11-2002	Tanaka, Yoshito	345/60
*	H	US-6,882,116	04-2005	Araki, Kota	315/169.4
*	I	US-2002/0186186	12-2002	HASHIMOTO et al.	345/63
*	J	US-5,420,602	05-1995	Kanazawa, Yoshikazu	345/67
*	K	US-6,768,478	07-2004	Wani et al.	345/60
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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